Record Nr. UNINA9910714160103321 Autore Zarr Robert R Titolo Standard reference materials: glass fiberboard SRM 1450c, for thermal resistance from 280 K to 340 K / / Robert R. Zarr Pubbl/distr/stampa Gaithersburg, MD:,: U.S. Dept. of Commerce, National Institute of Standards and Technology, , 1997 Descrizione fisica 1 online resource Collana NIST special publication; ; 260-130 Altri autori (Persone) ZarrRobert R Soggetti Materials - Standards - United States Weights and measures - United States Scientific apparatus and instruments - United States Scientific apparatus and instruments Materials - Standards Weights and measures **United States** Lingua di pubblicazione Inglese **Formato** Materiale a stampa Livello bibliografico Monografia 1997. Note generali Contributed record: Metadata reviewed, not verified. Some fields updated by batch processes. Title from PDF title page. Nota di bibliografia Includes bibliographical references. Nota di contenuto About NIST SRMs -- Ordering policies and pricing -- Registration and surveys -- SRM order request system -- Using the online catalog --SRM exhibits -- SRM definitions -- Publications (SP260s) -- Archived SRM certificates/reports of investigation -- New SRM/RMs -- Standard reference instruments. Sommario/riassunto NIST supports accurate and compatible measurements by certifying and providing over 1300 Standard Reference Materials® with wellcharacterized composition or properties, or both. These materials are used to perform instrument calibrations in units as part of overall quality assurance programs, to verify the accuracy of specific measurements and to support the development of new measurement

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